

## Notice of References Cited

Application/Control No. 09/755,530		Reexamination	Applicant(s)/Patent Under Reexamination SCHMUTZ ET AL.		
	Examiner	Art Unit			
	Christine Na	2663	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,958,213	05-1976	Scott et al.	340/566
	В	US-5,029,162	07-1991	Epps, David C.	370/252
	C	US-5,050,192	09-1991	Nawata, Hizuru	375/345
	۵	US-5,091,725	02-1992	Gard, Michael F.	340/854.1
	E	US-5,184,349	02-1993	Riordan, Kenneth B.	370/347
	F	US-5,251,216	10-1993	Marshall et al.	370/337
	G	US-5,548,594	08-1996	Nakamura, Naoyuki	370/347
	Н	US-5,852,412	12-1998	Stangeland, Rodney L.	340/988
	ı	US-6,028,886	02-2000	Koga et al.	375/133
	J	US-6,115,591	09-2000	Hwang, In-Kyou	455/277.2
	K	US-6,317,435	11-2001	Tiedemann et al.	370/441
	L	US-6,370,386	04-2002	Williams, Terry L.	455/452.1
	М	US-6,456,606	09-2002	Terasawa, Daisuke	370/331

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р	\				
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.